10/09/2025 Events

The working visit of the official delegation of the State Office for Inventions and Trademarks of Romania (OSIM) took place during the period 6–9 October 2025 to the State Agency on Intellectual Property (AGEPI), organized for the purpose of exchanging experience in the field of protection of topographies of semiconductor products and substantive examination of patent applications for inventions in the field of computer programs.

The visit was part of the series of bilateral cooperation actions between AGEPI and OSIM, focused on strengthening institutional capacities and exchanging good practices in the field of industrial property.

The OSIM delegation was represented by Ms. Daniela Cristudor and Anca Popescu, examiners within the Electricity-Physics Substantive Examination Service of OSIM, who had a series of meetings and working sessions with specialists from the Patents Directorate and IT specialists from AGEPI.

During the two days of activity, the participants addressed a series of technical and procedural topics regarding the procedure for registration of a topography of semiconductor product, including the content of the application, the technical documentation and the examination stages up to publication in BOPI, the management of the topography database, as well as aspects of the substantive examination of patent applications for computer-implemented inventions.

The specialists also conducted a case study on a topography registration application, analyzed in detail by OSIM and AGEPI experts, and discussed a series of practical questions regarding the delimitation of patentable objects in the case of inventions based on algorithms, neural networks, information encryption processes and automation solutions involving artificial intelligence.

The event ended with a joint assessment of the results of the exchange of experience, the parties confirming their interest in continuing cooperation and organizing new thematic meetings dedicated to capacity building in the field of industrial property.


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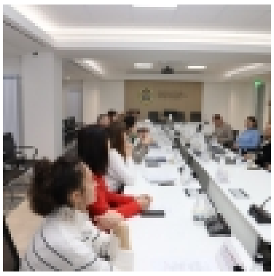

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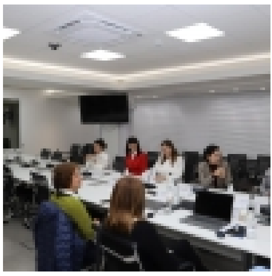

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